

				ATTY DOCKET NO. <b>BUR920040089US1</b>		APPLICATION NO.	
				APPLICANT(S) <b>Voldman et al.</b>			
				FILING DATE		GROUP ART UNIT <b>Unknown</b>	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
<b>WLL</b>	4,578,128	03/25/86	Mundt et al.	—	—		
<b>WLL</b>	4,486,266	12/04/84	Yamaguchi	—	—		
<b>WLL</b>	4,862,233	08/29/89	Matsushita et al.	—	—		
<b>WLL</b>	4,729,006	03/01/88	Dally et al.	—	—		
<b>WLL</b>	4,656,730	04/14/87	Lynch et al.	—	—		
<b>U.S. PATENT APPLICATION PUBLICATIONS</b>							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
<b>WLL</b>	2002/0135024	09/26/02	Logan et al.	—	—		
<b>WLL</b>	2003/0205765	11/06/03	Masuoka	—	—		
<b>FOREIGN PATENT DOCUMENTS</b>							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	
<b>WLL</b>	JP63-304661	12/12/88	Japan	—	—		
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
<b>WLL</b>	Voldman et al., "Retention Time and Soft Error Rate Improvement by Tailoring Well Doping in Trench Dram Cells", IBM Technical Disclosure Bulletin, Vol. 33, No. 1B, 1990, pp. 35-36.						
<b>WLL</b>	L.A. Nesbit, "Method of Forming Shallow Trench Isolation With Selectively Doped Sidewalls, Vol. 31 No. 2, 1988, pp. 418-420.						
EXAMINER <b>WLL</b>				DATE CONSIDERED <b>3/24/05</b>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>	ATTY DOCKET NO. <b>BUR920040089US1</b>	APPLICATION NO.
	Voldman et al.	
	FILING	GROUP ART <b>Unknown</b>

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
WLL	4,926,233	05/15/90	Hutter	—	—	
WLL	5,067,002	11/19/91	Zdebel et al.	—	—	
WLL	5,612,242	03/18/97	Hsu	—	—	
WLL	6,514,833	02/04/03	Ishida et al.	—	—	
WLL	6,600,199	07/29/03	Voldman et al.	—	—	

**U.S. PATENT APPLICATION PUBLICATIONS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

**FOREIGN PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER <i>W. L. L. L.</i>	DATE CONSIDERED <b>3/24/05</b>
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<b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)	ATTY DOCKET NO. BUR920040089US1	APPLICATION NO.
	Voldman et al.	
	FILING	GROUP ART Unknown

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
WLL	5,780,353	07/14/98	Omid-Zohoor	—	—	
WLL	6,518,628	01/11/03	Krautschneider et al.	—	—	

**U.S. PATENT APPLICATION PUBLICATIONS**

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

**FOREIGN PATENT DOCUMENTS**

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER <i>Walt L. Luber</i>	DATE CONSIDERED <i>3/24/05</i>
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